
**Test methods for machine readable
travel documents (MRTD) and
associated devices —**

**Part 2:
Test methods for the contactless
interface**

*Méthodes d'essai pour les documents de voyage lisibles par machine
(MRTD) et dispositifs associés —*

Partie 2: Méthodes d'essai de l'interface sans contact

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Foreword

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The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of document should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

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This document was prepared by ISO/IEC JTC 1, *Information technology*, SC 17, *Cards and security devices for personal identification*.

This second edition cancels and replaces the first edition (ISO/IEC 18745-2:2016), which has been technically revised.

The main changes compared to the previous edition are as follows:

- simplification of the test conditions for PCD in terms of temperature;
- modification of the loading effect required for eMRTD.

A list of all parts in the ISO/IEC 18745 series can be found on the ISO website.

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